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60V N-Channel Enhancement Mode MOSFET

Description

The XPX5N06AS uses advanced trench technology

to provide excellent $R_{\text{DS}(\text{ON})}\text{,}$ low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

General Features

V_{DS} = 60V I_D =5A

 $R_{DS(ON)}$ < 28m Ω @ V_{GS}=10V

Application

Battery protection

Load switch

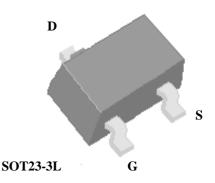
Automative lighting

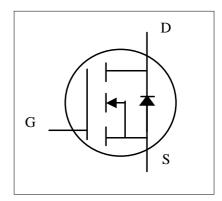
Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
XPX5N06AS	SOT-23-3L	NA6-5A	3000

Absolute Maximum Ratings (Tc=25°Cunless otherwise note

Symbol	Parameter	Rating	Units	
Vds	Drain-Source Voltage	60	V	
Vgs	Gate-Source Voltage	±20	V	
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	5	А	
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ 10V ¹	3.5	А	
Ідм	Pulsed Drain Current ²	18	А	
EAS	Single Pulse Avalanche Energy ³	22	mJ	
las	Avalanche Current	21	А	
P _D @T _A =25°C	Total Power Dissipation ⁴	1.5	W	
Тѕтс	Storage Temperature Range	-55 to 150	°C	
TJ	Operating Junction Temperature Range	-55 to 150	°C	
R ₀ JA	Thermal Resistance Junction-ambient ¹	85	°C/W	
Rejc	Thermal Resistance Junction-Case ¹	25	°C/W	







Parameter	Conditions	Min.	Тур.	Max.	Unit	
Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60			V	
BVDSS Temperature Coefficient	Reference to 25 $^\circ\!\!\mathbb{C}$, I_D=1mA		0.044		V/℃	
Static Drain, Source On-Resistance ²	V _{GS} =10V , I _D =4A		28	38	mΩ	
	V _{GS} =4.5V , I _D =2A	V _{GS} =4.5V , I _D =2A 35		50	11152	
Gate Threshold Voltage	Vce=Vce_lp=250uA	1.0	1.76	2.5	V	
V _{GS(th)} Temperature Coefficient	VG3-VD3, 10-2000/		-4.8		mV/° ℃	
Drein Source Lookage Current	V _{DS} =48V , V _{GS} =0V , T _J =25℃			1	uA	
Drain-Source Leakage Current	V _{DS} =48V , V _{GS} =0V , TJ=55℃		5		uA	
Gate-Source Leakage Current	V_{GS} =±20V , V_{DS} =0V			±100	nA	
Forward Transconductance	V _{DS} =5V , I _D =4A		28.3		S	
Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		2.5		Ω	
Total Gate Charge (10V)			19			
Gate-Source Charge	V _{DS} =48V , V _{GS} =10V , I _D =4A		2.6		nC	
Gate-Drain Charge			4.1			
Turn-On Delay Time			3			
Rise Time			34			
Turn-Off Delay Time			23		ns	
Fall Time			6			
Input Capacitance			1027			
Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		65		pF	
Reverse Transfer Capacitance			46			
Continuous Source Current ^{1,5}				4.5	А	
Pulsed Source Current ^{2,5}	V _G =V _D =0V , Force Current			18	А	
Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , TJ=25℃			1.2	V	
Reverse Recovery Time	I _F =4A , dI/dt=100A/µs ,		12.1		nS	
	Drain-Source Breakdown Voltage BVDSS Temperature Coefficient Static Drain-Source On-Resistance ² Gate Threshold Voltage VGS(th) Temperature Coefficient Drain-Source Leakage Current Gate-Source Leakage Current Forward Transconductance Gate Resistance Total Gate Charge (10V) Gate-Source Charge Gate-Drain Charge Gate-Drain Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Reverse Transfer Capacitance Continuous Source Current ^{1,5} Pulsed Source Current ^{2,5} Diode Forward Voltage ²	$\begin{tabular}{ c c c c } \hline Drain-Source Breakdown Voltage & V_{GS}=0V , l_{D}=250uA \\ \hline Reference to 25 °C , l_{D}=1mA \\ \hline Reference to 25 °C , l_{D}=1mA \\ \hline V_{GS}=10V , l_{D}=4A \\ \hline V_{GS}=4.5V , l_{D}=2A \\ \hline V_{GS}(h) Temperature Coefficient \\ \hline Drain-Source Leakage Current \\ \hline Drain-Source Leakage Current \\ \hline Drain-Source Leakage Current \\ \hline V_{DS}=48V , V_{GS}=0V , T_{J}=25 °C \\ \hline V_{DS}=48V , V_{GS}=0V , T_{J}=55 °C \\ \hline Gate-Source Leakage Current \\ \hline V_{DS}=48V , V_{GS}=0V , T_{J}=55 °C \\ \hline Gate-Source Leakage Current \\ \hline V_{DS}=48V , V_{GS}=0V , V_{DS}=0V \\ \hline Forward Transconductance \\ \hline V_{DS}=5V , l_{D}=4A \\ \hline Gate Resistance \\ \hline V_{DS}=0V , V_{GS}=0V , f=1MHz \\ \hline Total Gate Charge (10V) \\ \hline Gate-Source Charge \\ \hline Turn-On Delay Time \\ \hline Turn-On Delay Time \\ \hline Input Capacitance \\ \hline Output Capacitance \\ \hline Output Capacitance \\ \hline Continuous Source Current^{1.5} \\ \hline V_{G}=V_{D}=0V , Force Current \\ \hline Pulsed Source Current^{2.5} \\ \hline Diode Forward Voltage^2 \\ \hline V_{GS}=0V , l_{S}=1A , T_{J}=25 °C \\ \hline \end{tabular}$	$\begin{array}{c c c c c c } \hline \mbox{Drain-Source Breakdown Voltage} & V_{GS}=0V , \mbox{Ib}=250uA & 60 \\ \hline \mbox{BVDSS Temperature Coefficient} & Reference to 25 °C , \mbox{Ib}=1mA & \\ \hline \mbox{VGS} Temperature Coefficient & V_{GS}=10V , \mbox{Ib}=2A & \\ \hline \mbox{VGS}(th) Temperature Coefficient & V_{GS}=V_{DS} , \mbox{Ib}=250uA & 1.0 \\ \hline \mbox{VGS}(th) Temperature Coefficient & V_{GS}=V_{DS} , \mbox{Ib}=250uA & \\ \hline \mbox{VGS}(th) Temperature Coefficient & V_{DS}=48V , V_{GS}=0V , \mbox{TJ}=25 °C & \\ \hline \mbox{VGS}(th) Temperature Coefficient & V_{DS}=48V , V_{GS}=0V , \mbox{TJ}=25 °C & \\ \hline \mbox{VGS}(th) Temperature Coefficient & V_{DS}=48V , V_{GS}=0V , \mbox{TJ}=25 °C & \\ \hline \mbox{Gate-Source Leakage Current & V_{DS}=5V , \mbox{Ib}=4A & \\ \hline \mbox{Gate Resistance & V_{DS}=0V , \mbox{VGS}=0V , \mbox{f}=1MHz & \\ \hline \mbox{Gate-Source Charge (10V) & V_{DS}=48V , \mbox{VGS}=10V , \mbox{Ib}=4A & \\ \hline \mbox{Gate-Source Charge (10V) & V_{DS}=48V , \mbox{VGS}=10V , \mbox{Ib}=4A & \\ \hline \mbox{Gate-Source Charge (10V) & V_{DS}=48V , \mbox{VGS}=10V , \mbox{Ib}=4A & \\ \hline \mbox{Gate-Drain Charge & V_{DS}=30V , \mbox{VGS}=10V , \mbox{Ib}=4A & \\ \hline \mbox{Iurn-On Delay Time & Ib_{D}=30V , \mbox{VGS}=10V , \mbox{Re}=3.3\Omega & \\ \hline \mbox{Iurn-Off Delay Time & Ib_{D}=4A & \\ \hline \mbox{Iurn-Off Delay Time & Ib_{D}=4A & \\ \hline \mbox{Iurn-Off Delay Time & V_{DS}=15V , \mbox{VGS}=0V , \mbox{f}=1MHz & \\ \hline \mbox{Iurn-Off Delay Capacitance & V_{DS}=15V , \mbox{VGS}=0V , \mbox{f}=1MHz & \\ \hline \mbox{Iuput Capacitance & V_{DS}=15V , \mbox{VGS}=0V , \mbox{f}=1MHz & \\ \hline \mbox{Iuput Capacitance & V_{DS}=0V , \mbox{F}=1MHz & \\ \hline \mbox{Iuput Capacitance & V_{DS}=0V , \mbox{F}=1MHz & \\ \hline \mbox{Iuput Capacitance & V_{DS}=0V , \mbox{F}=1MHz & \\ \hline \mbox{Iuput Capacitance & V_{DS}=0V , \mbox{F}=1MHz & \\ \hline \mbox{Iuput Capacitance & V_{DS}=0V , \mbox{F}=1MHz & \\ \hline \mbox{Iuput Capacitance & V_{DS}=0V , \mbox{F}=1A , \mbox{J}=25 °C & \\ \hline \mbox{Iuput Capacitance & V_{DS}=0V , \mbox{F}=1A , \$	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Note :

 $1_{\mbox{\tiny N}}$ The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.

 $2\,{\scriptstyle \sim}\,$ The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%

 $3_{\rm N}$ The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=21A

 $4\,{\scriptstyle \sim}\,$ The power dissipation is limited by 150°C junction temperature

 $5\,$ $\sim\,$ The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.



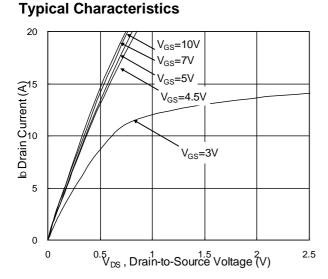


Fig.1 Typical Output Characteristics

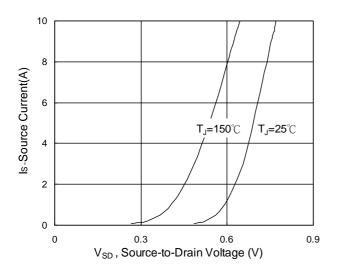


Fig.3 Forward Characteristics Of Reverse

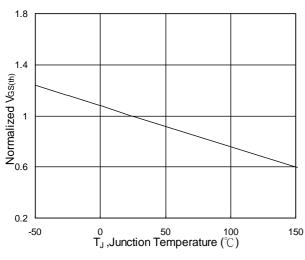


Fig.5 Normalized V_{GS(th)} vs. T_J

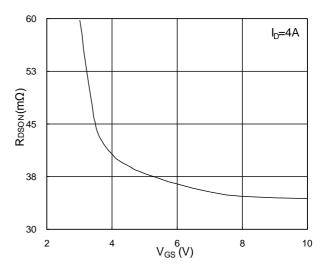


Fig.2 On-Resistance vs. Gate-Source

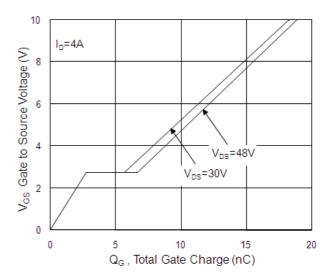


Fig.4 Gate-Charge Characteristics

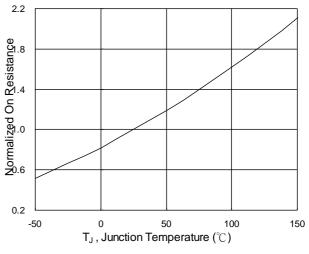


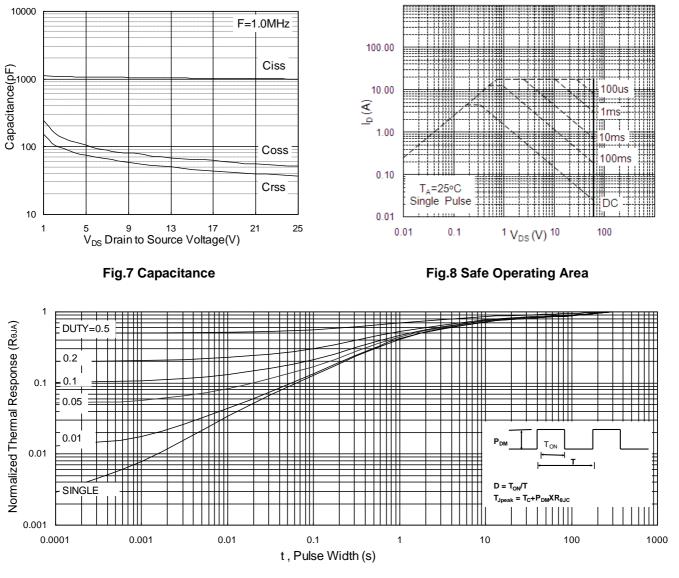
Fig.6 Normalized RDSON vs. TJ

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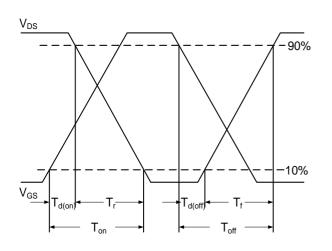


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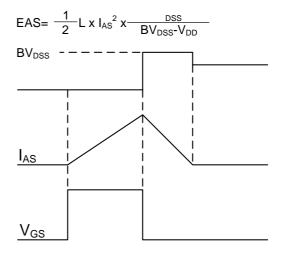
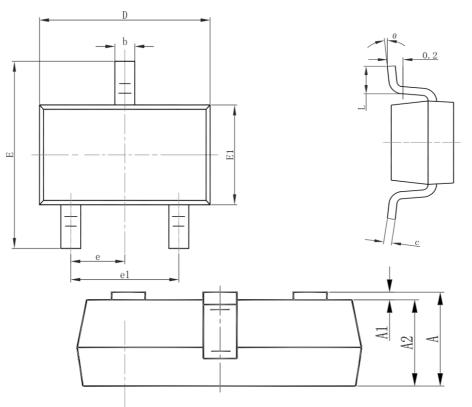


Fig.11 Unclamped Inductive Switching Waveform





Package Mechanical Data-SOT23-3



Symbol	Dimensions I	n Millimeters	Dimensio	ns In Inches
	Min.	Max.	Min.	Max.
А	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
с	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
е	0.950	(BSC)	0.03	7(BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°



Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245℃ ±5 ℃	5sec±1sec
Pb-Free device	260°C+0/-5°C	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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